

Microconcentrators for improving and augmenting focal planes

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Overview

We are fabricating microconcentrators to augment focal planes in order to improve detector fill factor and enable new imaging modes for compact telescopes, emphasizing CubeSats



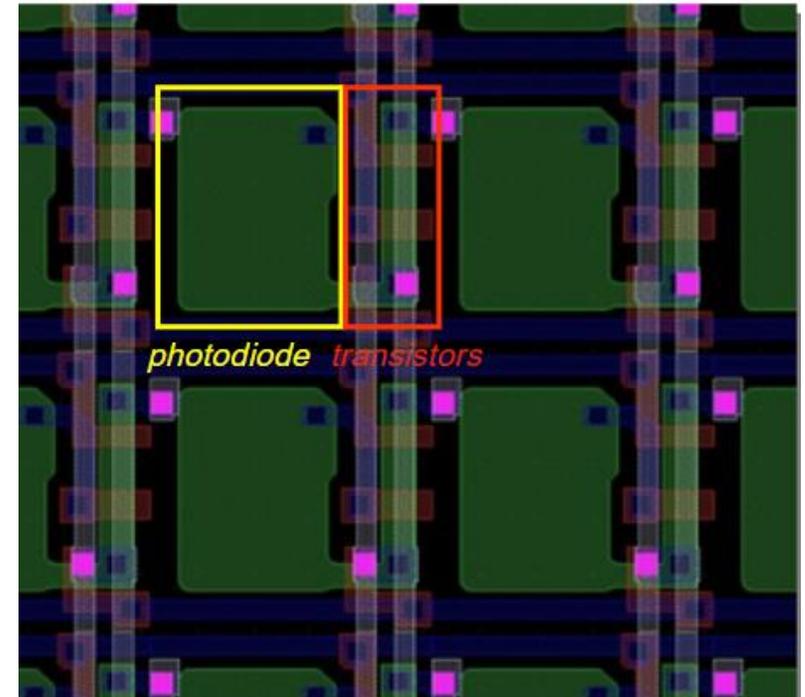
Nanohmics Background

- Based in Austin, TX
- Founded 2002
- Staff of ~35
 - Primarily scientists, engineers, and technicians
- 13,500 sq. ft. of industrial R&D flex space
- Member of the NNCI at University of Texas at Austin
- Core capabilities:
 - Microfabrication
 - Novel materials
 - Electro-optics
 - Instrumentation engineering
 - Sensors & diagnostics



State of the art

- Specialty focal planes often have extra electronics on each pixel, increases device complexity
 - Amplifiers, electronic bandpass filters, shutter control, etc.
- Actual “pixel” is not always square, and is often a small fraction of total area
 - Alternatively, vertical integration by bonding wafers with interconnects increases complexity & cost
 - For low-cost scientific CubeSats, often not an option
- Commonly, a microlens array is added to improve light collection
 - Can have chromatic effects
 - Often unsuitable in IR
 - Incomplete fill factor
 - High aspect ratio is tough
 - Often asymmetric angular acceptance
 - Some solutions can increase pixel-pixel crosstalk



M. Loose, A. Hoffman, V. Suntharalingam, CMOS Detector Technology, Scientific Detector Workshop, Sicily 2005

Motivation

- CubeSats have stringent limitations on size, mass, and cost
 - Need to miniaturize instruments with minimal compromise
- Nanohmics is developing novel chip-scale imaging technologies to improve and enhance COTS focal planes
- Our active CubeSat hyperspectral imaging NASA STTR program has a major fill factor challenge:
 - Need to bring $\sim 75\mu\text{m} \times 75\mu\text{m}$ superpixels down to $\sim 10 \times 10 \mu\text{m}$ area with minimal loss or chromatic bias
 - Without mitigating, getting $\sim 1\text{-}2\%$ total incident light into our microspectrometers



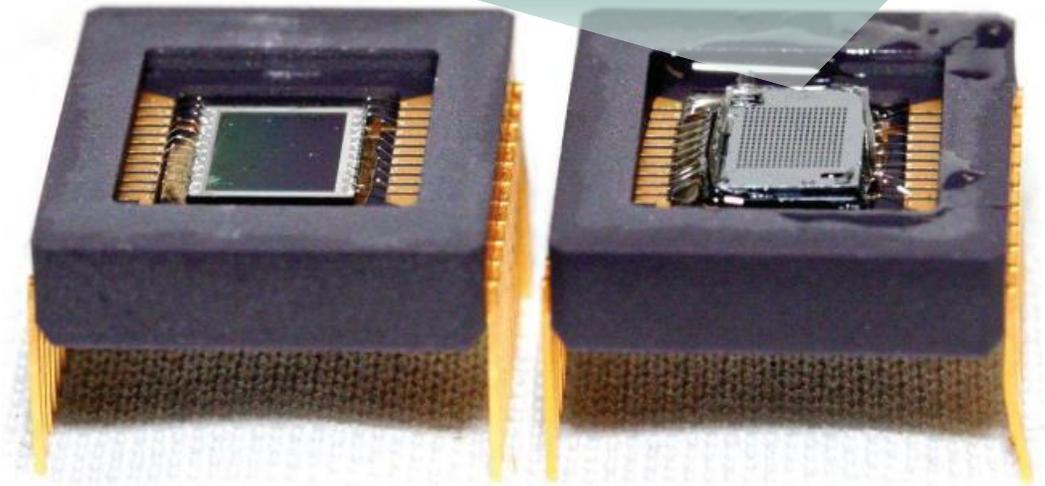
Solution:

- Fabricate microconcentrator arrays
- Microconcentrators are broadband micro-optical elements for maximizing detector fill factor
 - This can enable commercial detectors to operate closer to scientific-grade performance, or improve custom FPAs
 - Rely on reflection, not transmission; can be tailored for EUV-THz
- In most cases, expect to be able to find a configuration for $\geq 90\%$ collection, depending on IFOV
- We are interested in applying this to other sensors



Hyperspectral chip

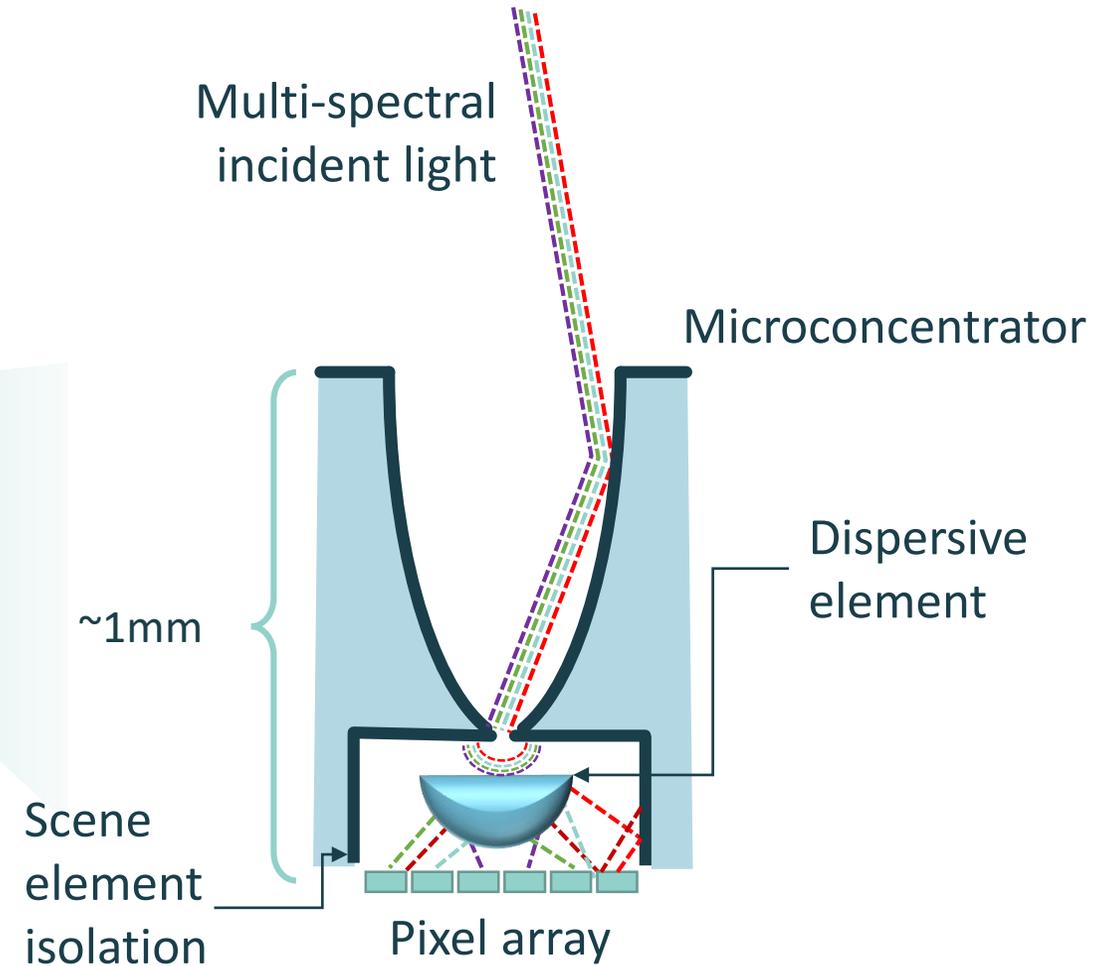
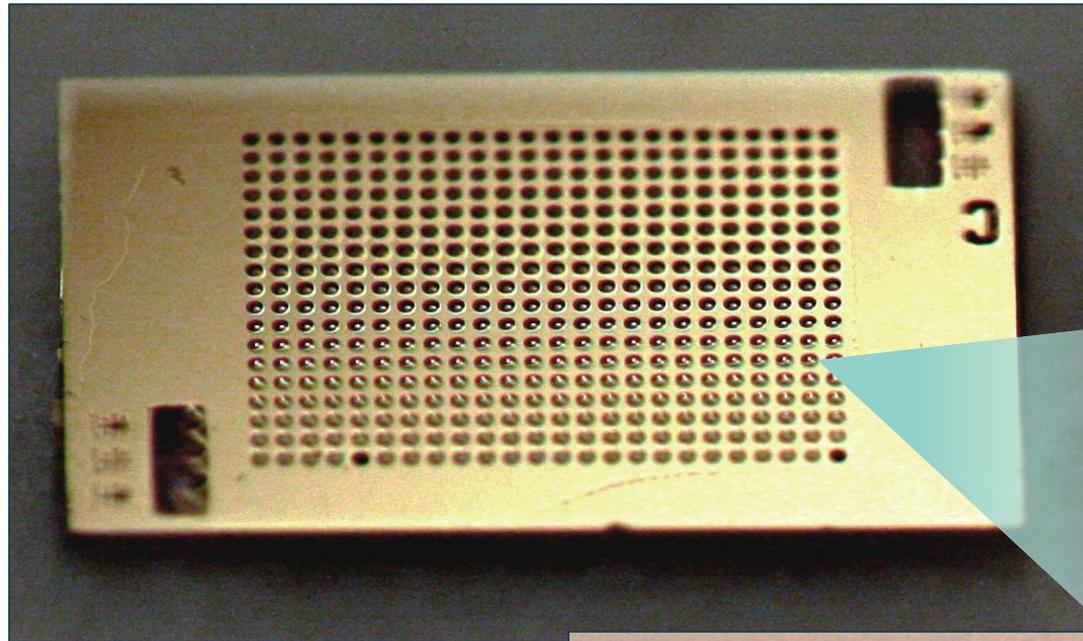
- Focal plane augmentation, add ~1 gram of mass by adding a chip onto, or very nearly on, an FPA
 - Shifts focal plane by ≤ 1 mm
- Our prototype hyperspectral chip is shown on right
 - Uses microconcentrator array



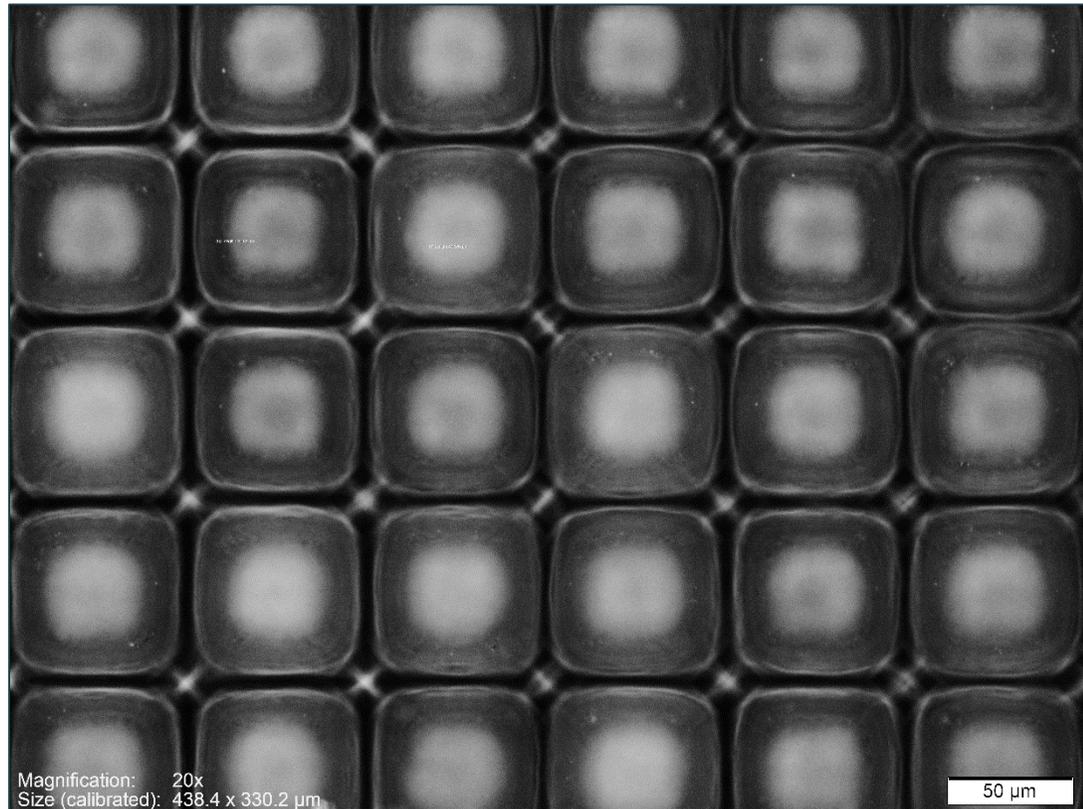
COTS FPA

Augmented FPA

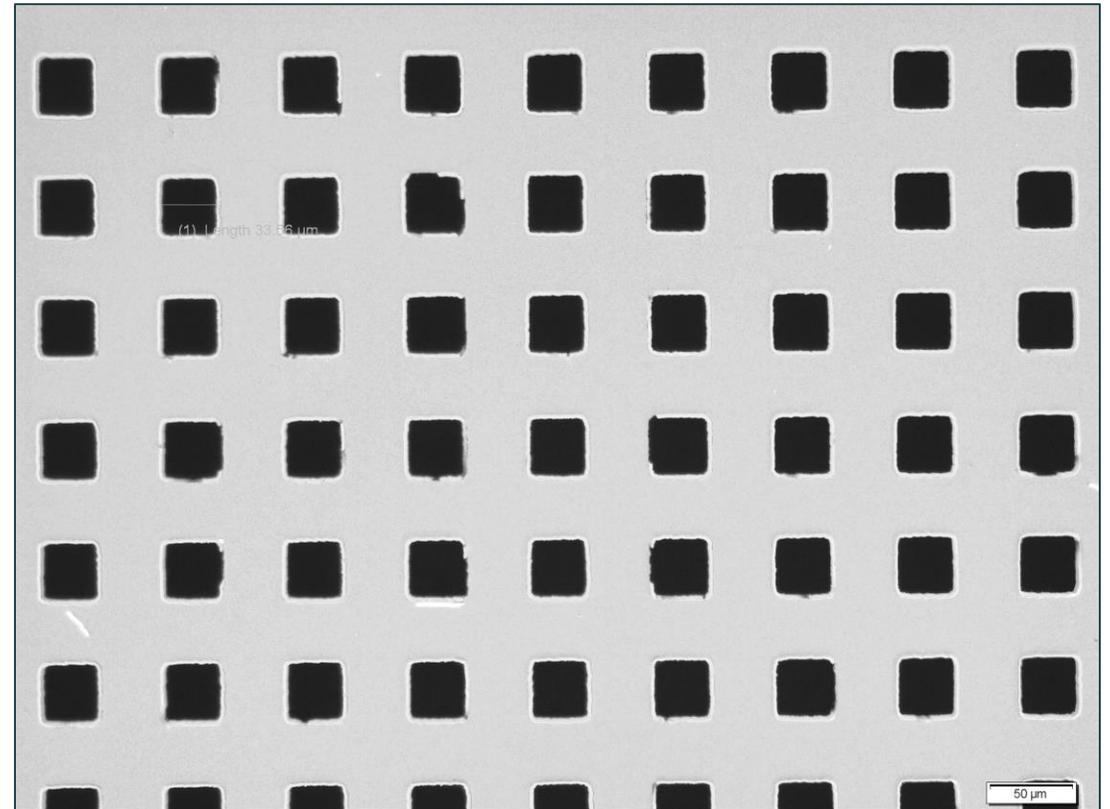
Hyperspectral chip technology



Optical concentration



Optical micrograph – view from top



Optical micrograph – view from bottom
(note, different sample)

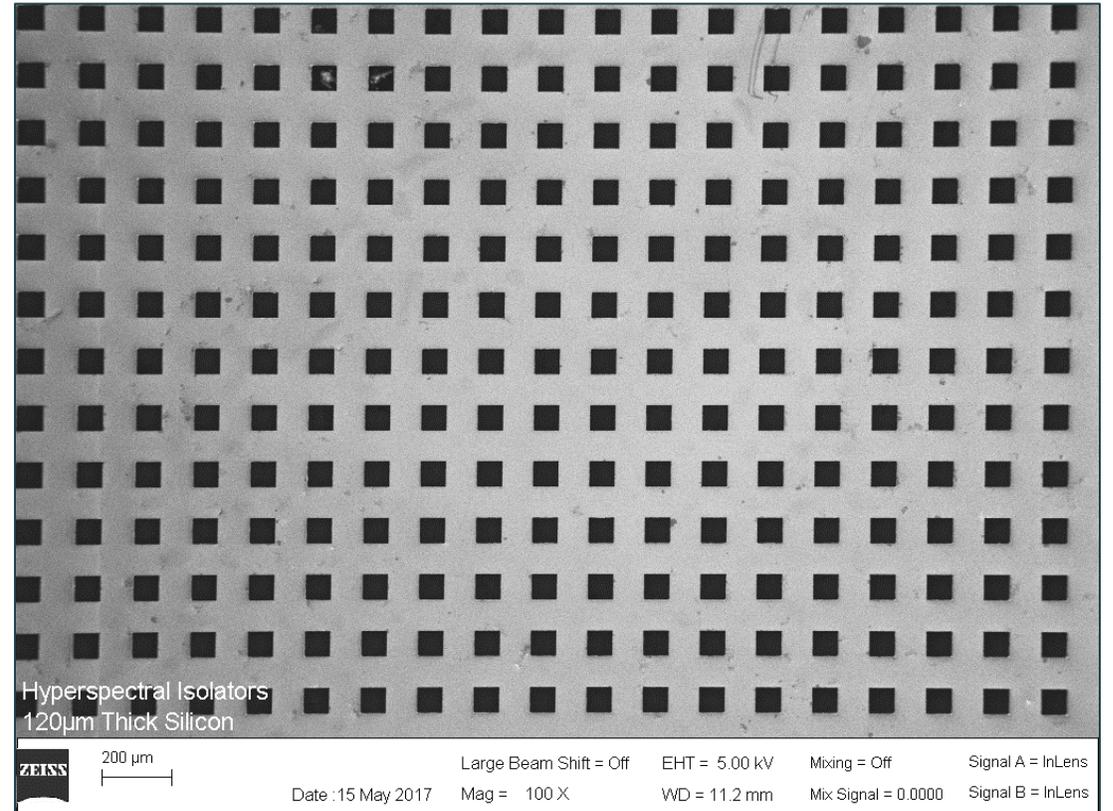
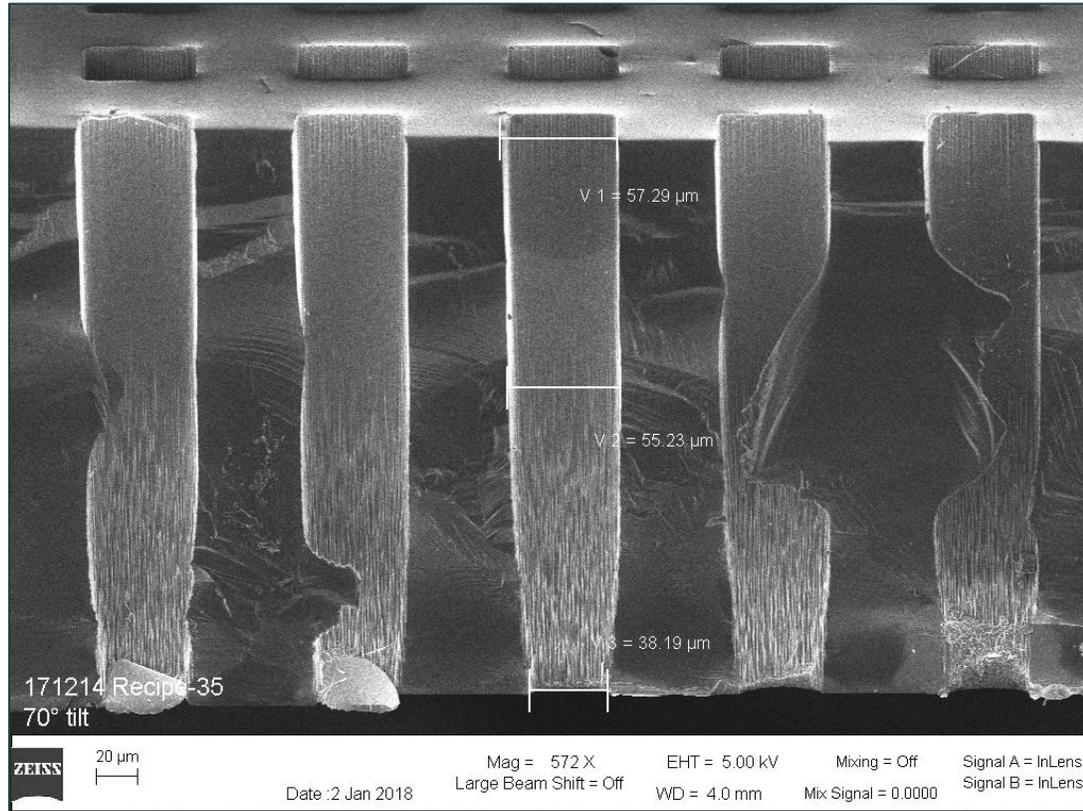
Sketch of process flow

1. Photolithography of desired pattern
2. Transfer pattern into a hard mask, such as Al_2O_3
3. Deep reactive ion etching, custom process
4. Post-etch smoothing (custom wet & plasma process)
5. Add reflective sidewall coating

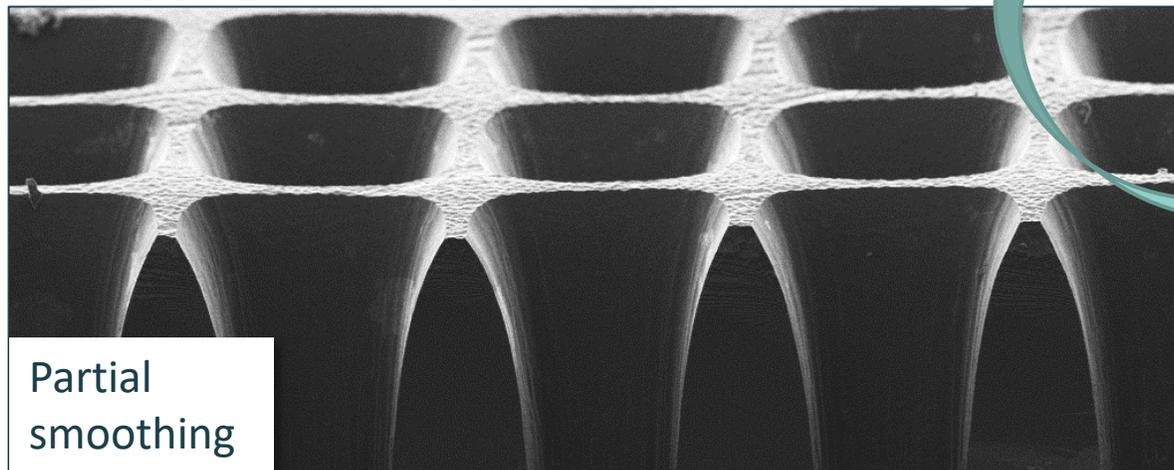
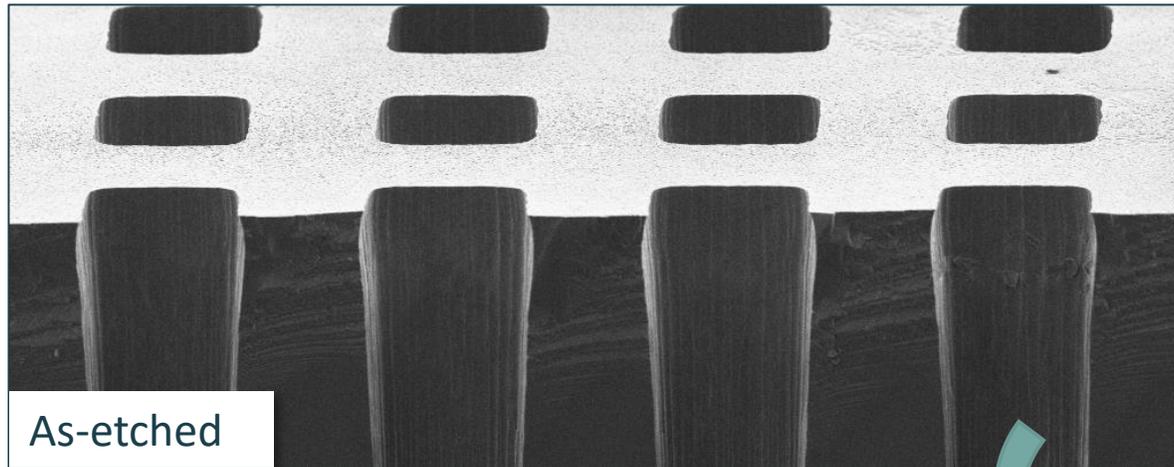


Microconcentrator SEMs

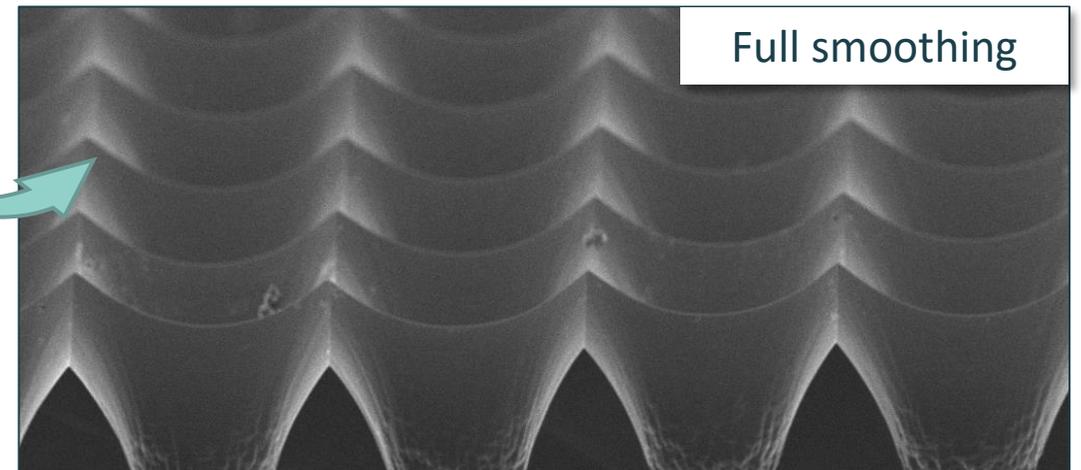
As etched, prior to smoothing



Tailoring concentrator entrance

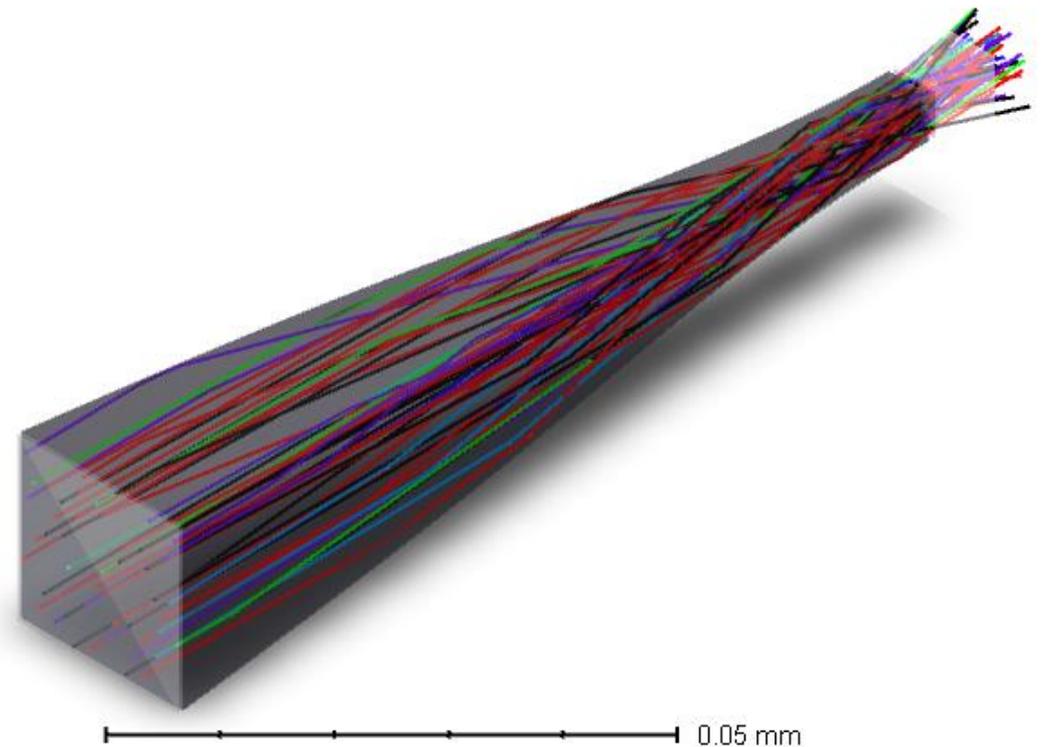


- Perform a post-etch sidewall cleanup to maximize fill factor, reduce roughness
- Tunable chemical & plasma etch processes



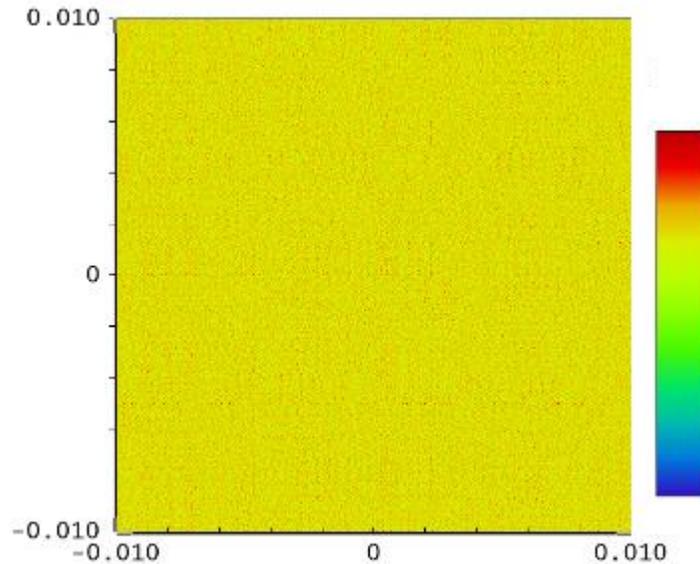
Models and simulations

- Zemax simulations of representative concentrator profiles
- Can include parameters like sidewall coating/roughness
- On right:
 - 20 μm pitch, 5 μm x 5 μm pixel
 - 100 μm long
 - No concentrator, 6.25% fill factor



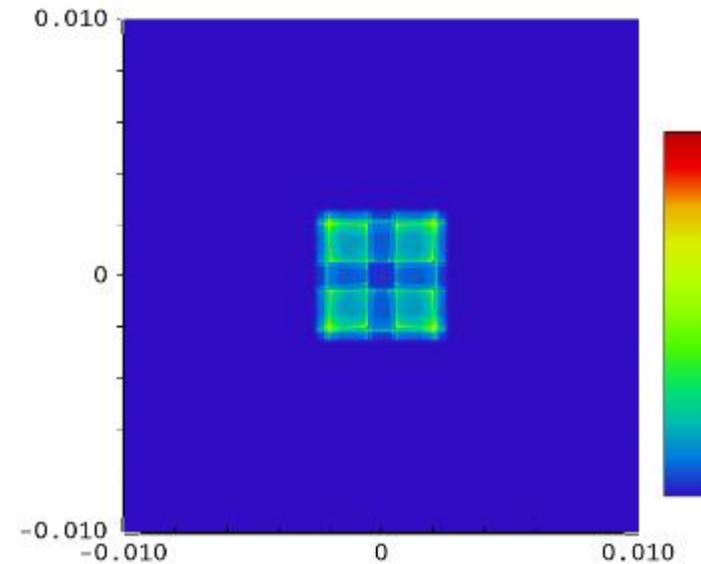
Normal incidence, 400-1000nm band

Incident rays



20µm x 20µm collection area

Spatial distribution at bottom of concentrator



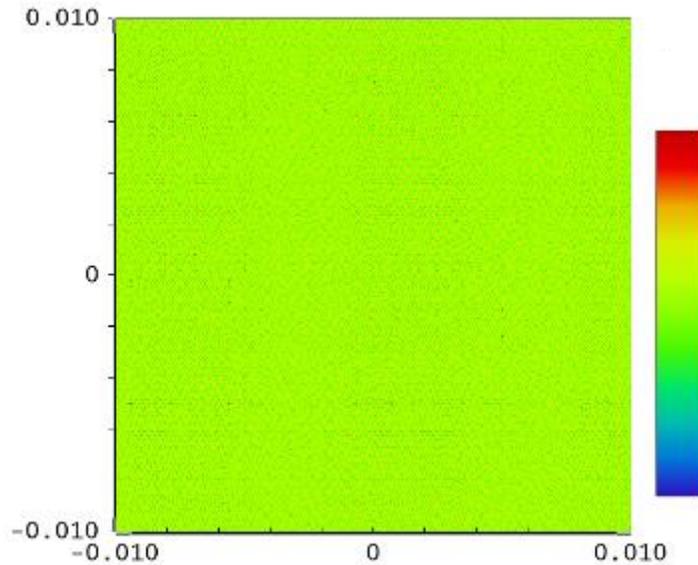
5µm x 5µm output

97.4% throughput with Ag sidewall coating



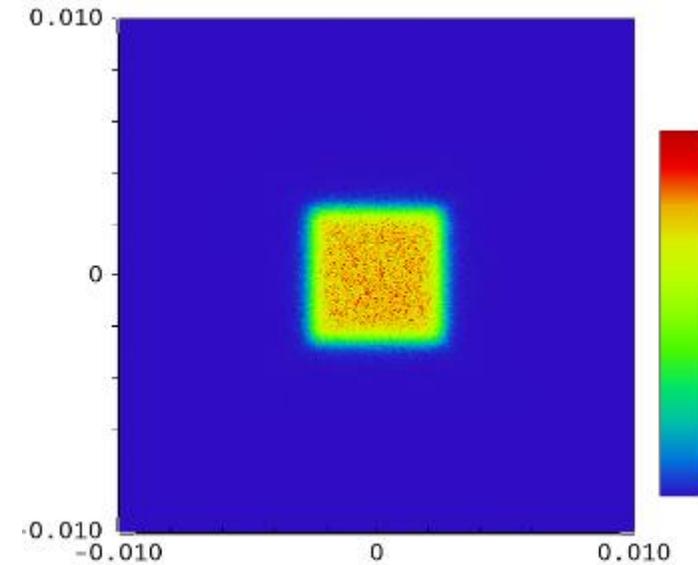
[+10°, -10°] incidence, 400-1000nm band

Incident rays



20µm x 20µm collection area

Spatial distribution at bottom of concentrator



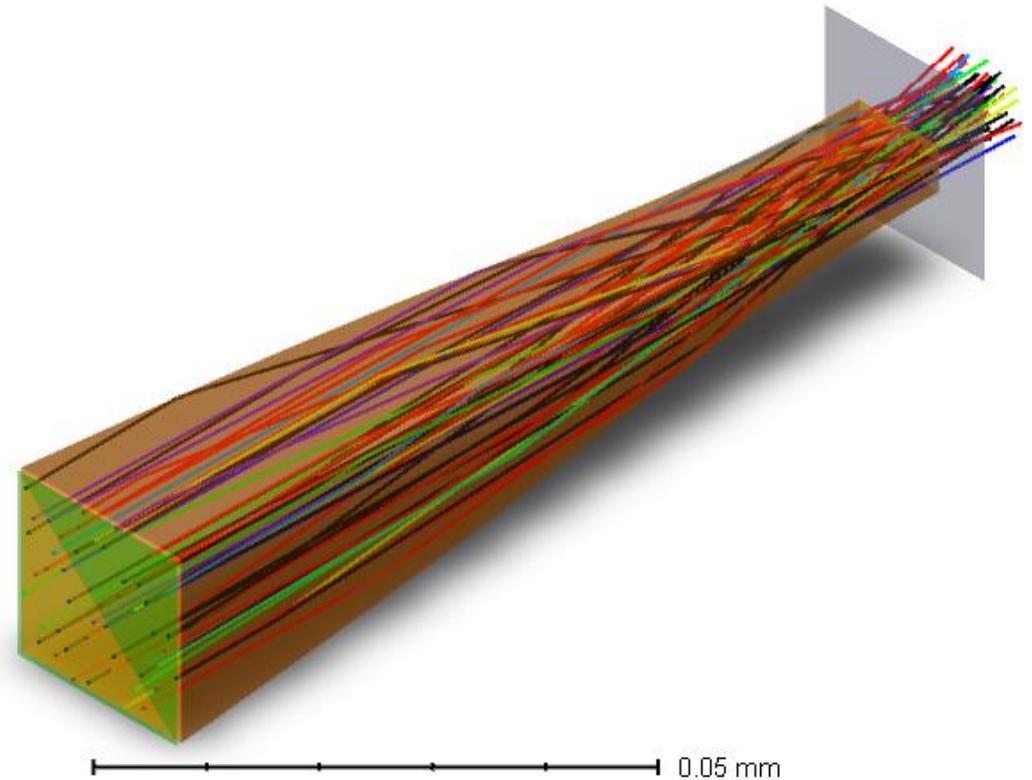
5µm x 5µm output

91.1% efficient with Ag sidewall coating



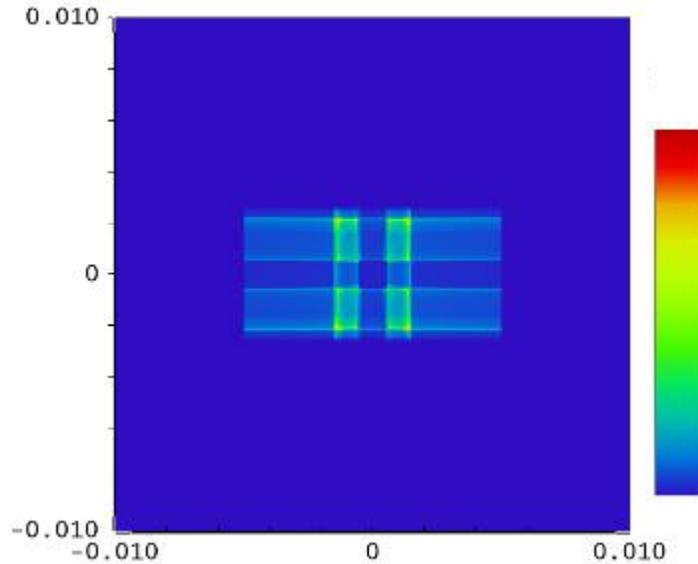
Models and simulations

- Double-side process enables different input and output geometries
- On right: square to rectangle
 - 20 μm pitch, 10 μm x 5 μm pixel
 - 100 μm long
 - No concentrator, 12.5% fill factor



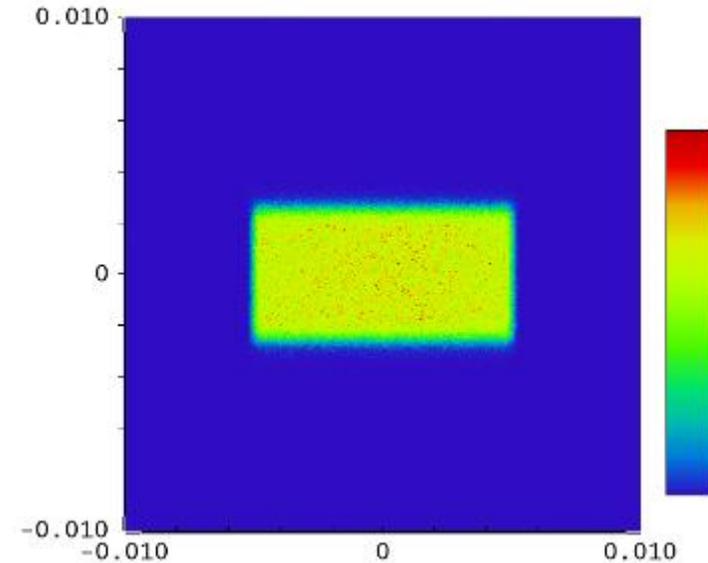
100 μm long, 20 μm pitch, 5 μm x 10 μm pixel

Normal incidence



98.4% efficient with Ag sidewall coating

[10°, -10°] uniformly distributed



95.0% efficient with Ag sidewall coating

Conclusions

- Microconcentrators can improve detector fill factor for EUV to THz
- Custom, lithographically defined input and output ports can be tailored to nearly any detector (COTS or custom)
- We are developing custom sidewall coatings for each wavelength band, currently focusing on VIS/NIR
- Wide acceptance angles are possible, good for low- f -number optics (like telescopes on CubeSats)
- Niche value-add component, can improve hardware after it's already designed
- We are interested in teaming on projects, let us know your application!
 - cmann@nanohmics.com

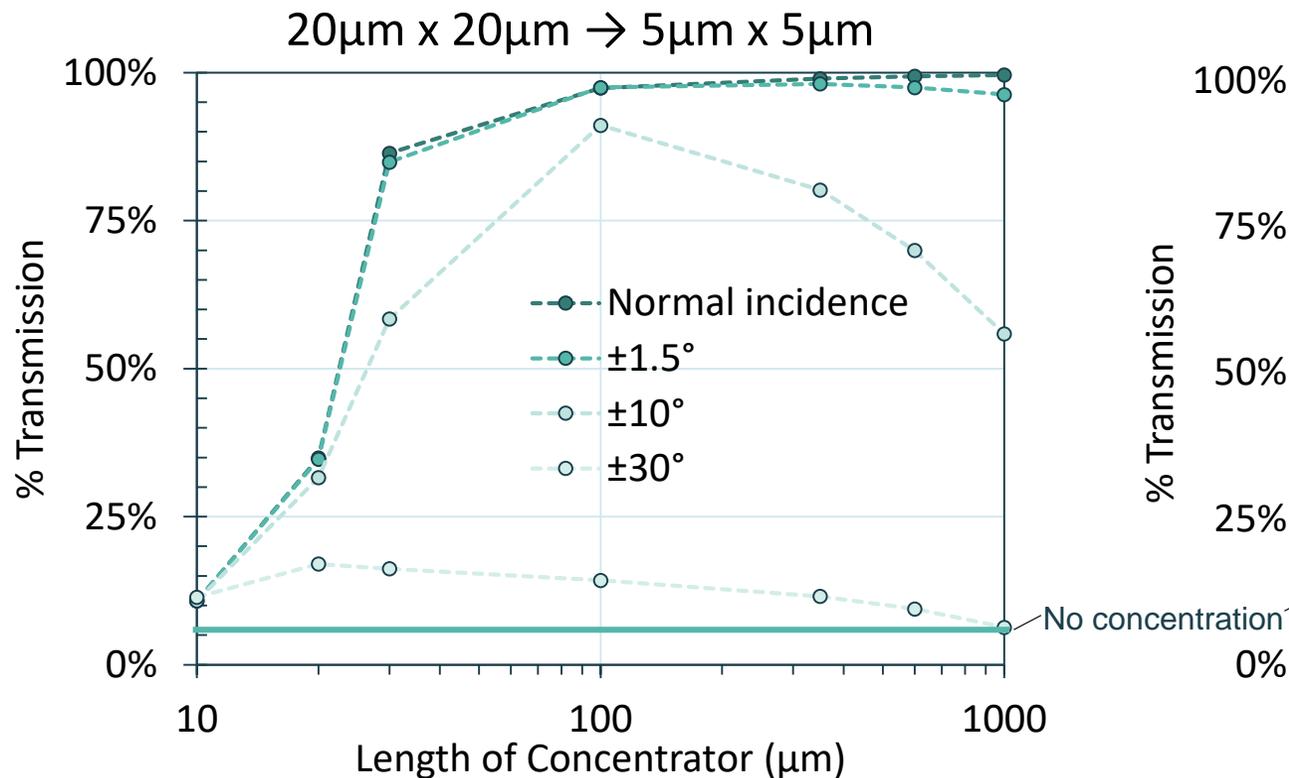


Questions?

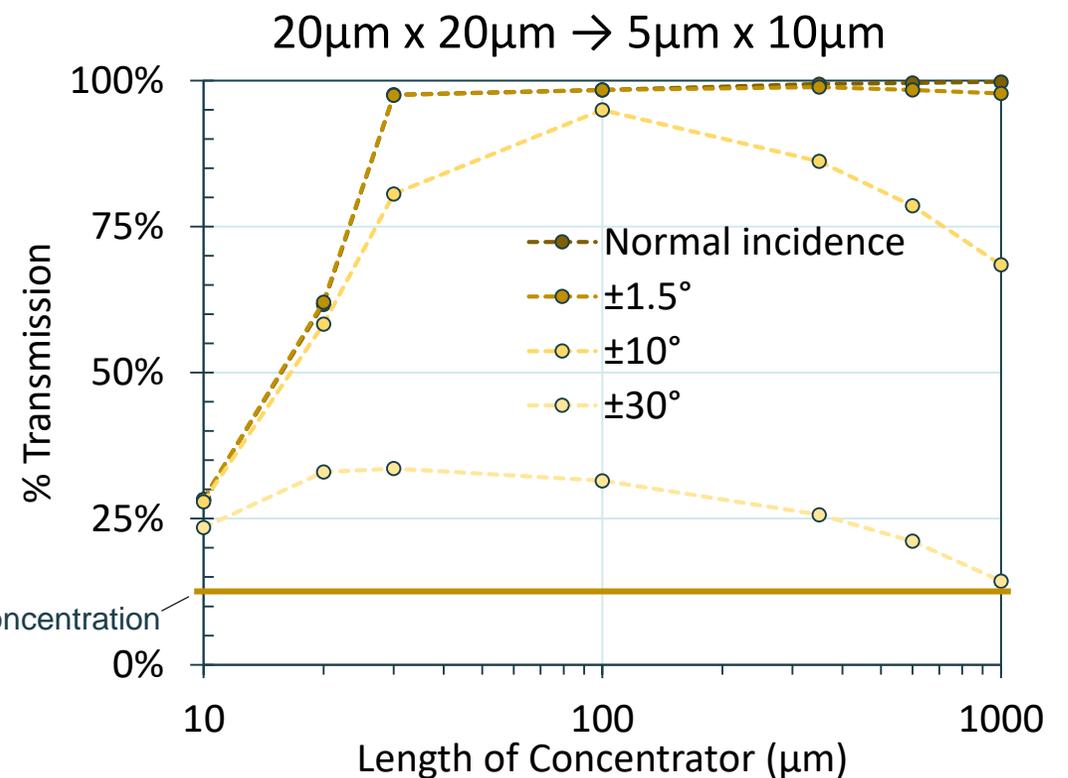


400-1000nm band simulation results

Square

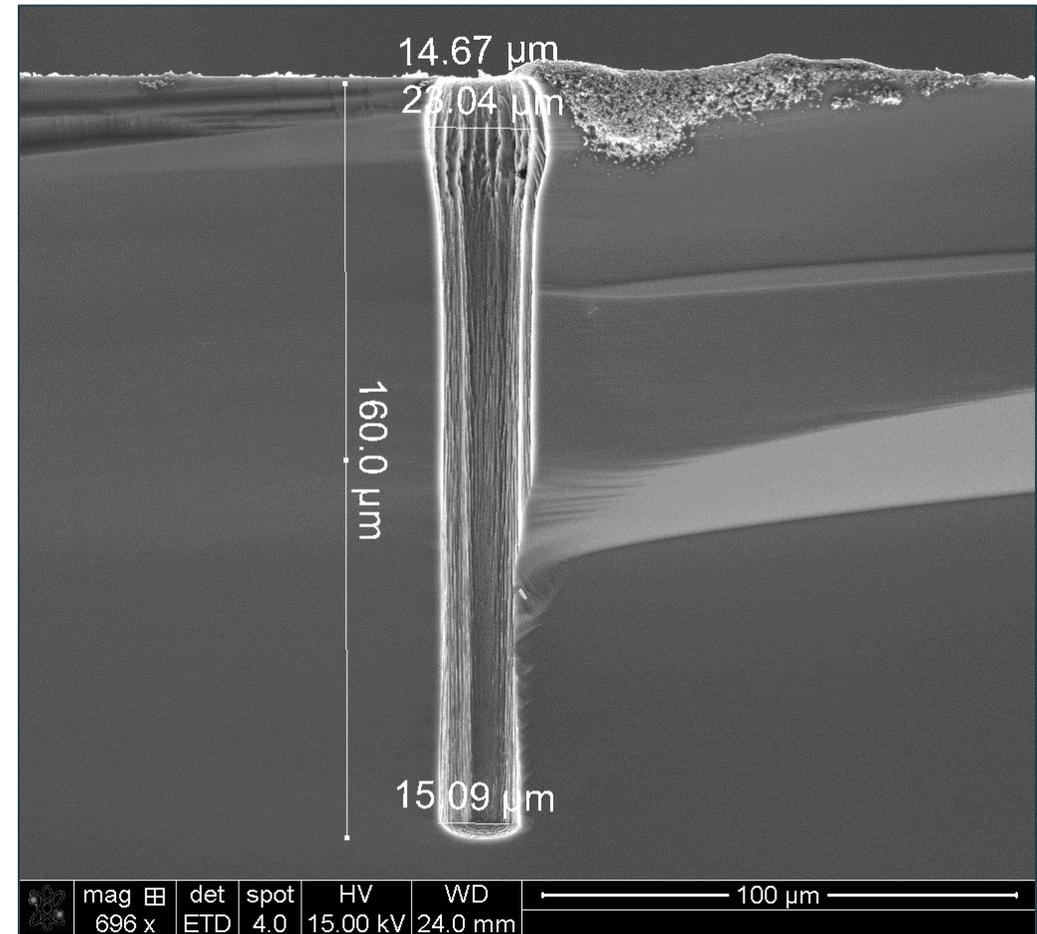


Rectangle



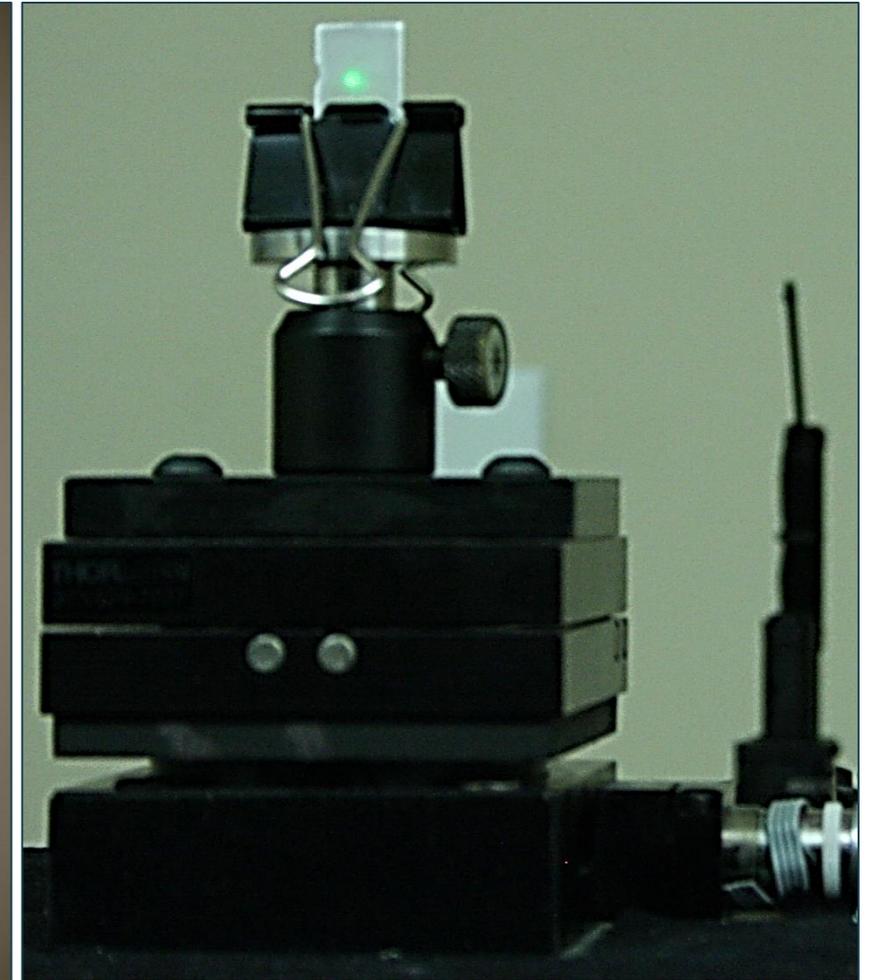
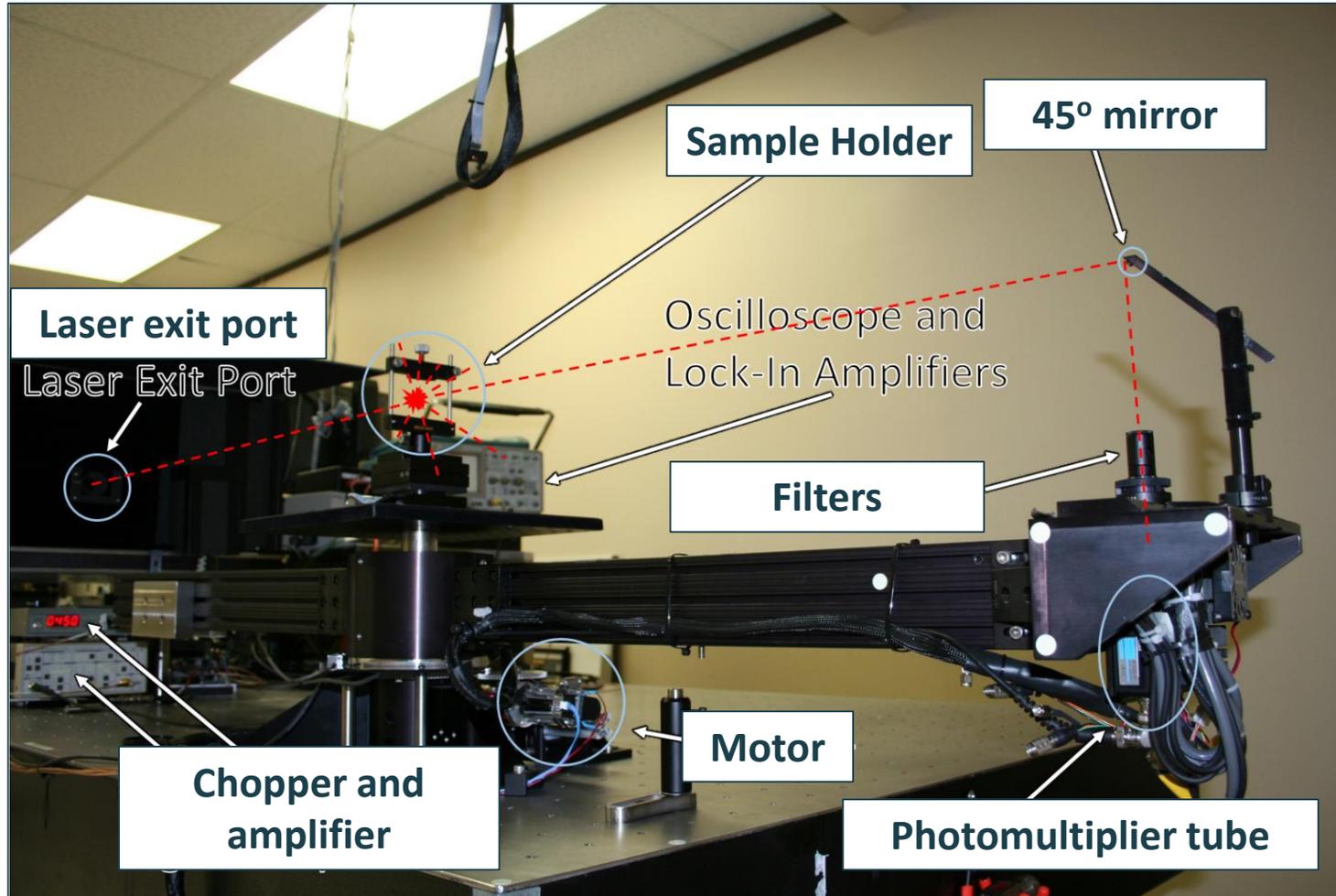
Accessible dimensions

- Original work was for 'superpixels,' typically 75-500 μm wide
- New work is exploring 5-50 μm regime (Right)
 - Viable for individual pixel optical concentration



Scatterometer

We offer full polarization-sensitive BRDF testing as a commercial service



Microconcentrator testing

- First light measurements shown on right
 - Uncoated Si concentrator array
- Broadband LED source
 - Lock-in signal
- Measure the relative intensity of light scattered into each angle as a function of input angle
 - Determine acceptance angle and sidewall reflection losses

